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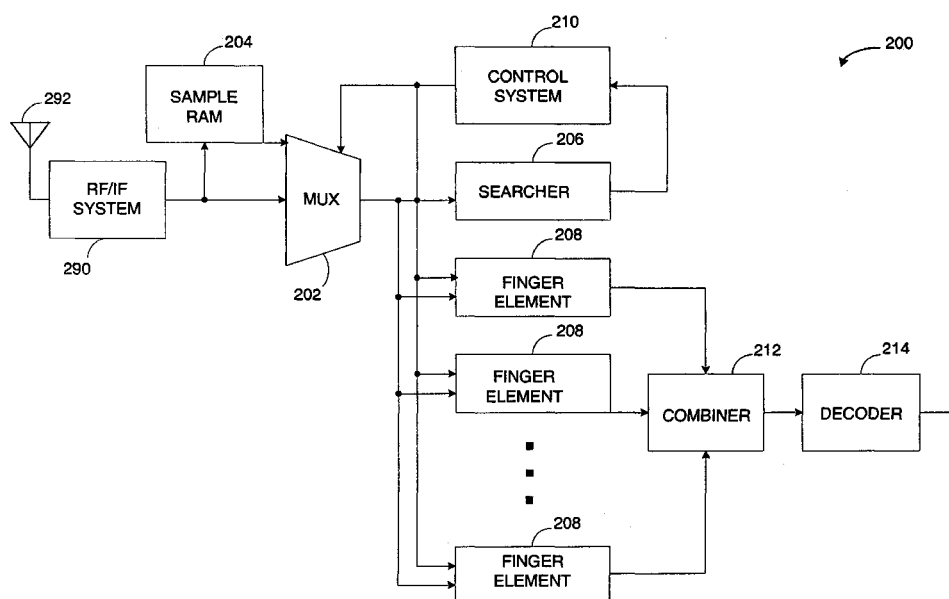
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For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

(54) Title: SIMPLIFIED QUALITY INDICATOR BIT TEST PROCEDURES



(57) Abstract: In a code division multiple access communication system, a method and apparatus provide for an efficient testing of operating behavior of a quality indicator bit. The method and the accompanying apparatus include configuring a receiver to expect to receive a communication channel at a full data rate, and transmitting a signal from a transmitter to the receiver. The signal is carrying the communication channel at a data rate other than said full data rate, and at a power level for receiving at the full data rate. Consequently, the receiver fails to receive the communication channel at the full data rate. A received signal to noise ratio of the received signal at the receiver is determined. A value of the quality indicator bit is determined based on the determined signal to noise ratio. The determined value of the quality indicator bit is communicated to the transmitter.